Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

| | IRFP450 | UNITS |
|---|------------|-------------------|
| Drain to Source Voltage (Note 1) V _{DS} | 500 | V |
| Drain to Gate Voltage (R_{GS} = 20k Ω) (Note 1) | 500 | V |
| Continuous Drain Current | 14 | А |
| $T_{C} = 100^{\circ}C$ I_{D} | 8.8 | А |
| Pulsed Drain Current (Note 3) | 56 | А |
| Gate to Source Voltage V _{GS} | ±20 | V |
| Maximum Power Dissipation | 180 | W |
| Linear Derating Factor | 1.44 | W/ ^o C |
| Single Pulse Avalanche Energy Rating (Note 4) E _{AS} | 860 | mJ |
| Operating and Storage Temperature | -55 to 150 | °C |
| Maximum Temperature for Soldering | | |
| Leads at 0.063in (1.6mm) from Case for 10s | 300 | °C |
| Package Body for 10s, See Techbrief 334 | 260 | °C |

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

| PARAMETER | SYMBOL | TEST CON | DITIONS | MIN | ТҮР | MAX | UNITS |
|---|---------------------|--|---|-----|------|------|-------|
| Drain to Source Breakdown Voltage | BV _{DSS} | I _D = 250μA, V _{GS} = 0V (Figure 10) | | 500 | - | - | V |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D = 250 \mu A$ | | 2.0 | - | 4.0 | V |
| Zero Gate Voltage Drain Current | IDSS | V_{DS} = Rated BV _{DSS} , V_{GS} = 0V V_{DS} = 0.8 x Rated BV _{DSS} , V_{GS} = 0V, T_J = 125°C | | - | - | 25 | μA |
| | | | | - | - | 250 | μA |
| On-State Drain Current (Note 2) | I _{D(ON)} | V _{DS} > I _{D(ON)} x r _{DS(ON)MAX} | , V _{GS} = 10V | 14 | - | - | A |
| Gate to Source Leakage Current | I _{GSS} | $V_{GS} = \pm 20V$ | | - | - | ±100 | nA |
| On Resistance (Note 2) | r _{DS(ON)} | $I_D = 7.9A$, $V_{GS} = 10V$ (Figure | res 8, 9) | - | 0.3 | 0.4 | Ω |
| Forward Transconductance (Note 2) | 9fs | $V_{DS} \ge 50V$, $I_D = 7.9A$ (Figur | re 12) | 9.3 | 13.8 | - | S |
| Turn-On Delay Time | t _{d(ON)} | $V_{DD} = 250V, I_D \approx 14A, V_{GS} = 10V, R_{GS} = 6.1\Omega,$ | | - | 16 | 27 | ns |
| Rise Time | t _r | $R_L = 17.4\Omega$ MOSFET Switc Essentially Independent of 0 | | - | 45 | 66 | ns |
| Turn-Off Delay Time | t _{d(OFF)} | Losentially independent of C | operating remperature | - | 68 | 100 | ns |
| Fall Time | t _f | - | | - | 41 | 60 | ns |
| Total Gate Charge (Gate to Source + Gate to Drain) | Q _{g(TOT)} | $\label{eq:VGS} \begin{array}{l} V_{GS} = 10V, \ I_D \approx 14A, \ V_{DS} = 0.8 \ x \ Rated \ BV_{DSS} \\ I_{G(REF)} = 1.5mA \ (Figure \ 14) \ Gate \ Charge \ is \\ Essentially \ Independent \ of \ OperatingTemperature \end{array}$ | | - | 82 | 130 | nC |
| Gate to Source Charge | Q _{gs} | | | - | 12 | - | nC |
| Gate to Drain "Miller" Charge | Q _{gd} | | | - | 42 | - | nC |
| Input Capacitance | C _{ISS} | $V_{DS} = 25V, V_{GS} = 0V, f = 1MHz$ (Figure 11) | | - | 2000 | - | pF |
| Output Capacitance | C _{OSS} | | | - | 400 | - | pF |
| Reverse Transfer Capacitance | C _{RSS} | | | - | 100 | - | pF |
| Internal Drain Inductance | LD | Measured from the Contact Screw on Header Closer to Source and Gate Pins to Center of Die | Modified MOSFET Symbol Showing the Internal Device Inductances | - | 5.0 | - | nH |
| Internal Source Inductance | LS | Measured from the Source Lead, 6.0mm (0.25in) from Header to Source Bonding Pad | G C C C C C C C C C C C C C C C C C C C | - | 12.5 | - | nH |
| Thermal Resistance, Junction to Case | R _{θJC} | | | - | - | 0.70 | °C/W |
| Thermal Resistance, Junction to Ambient | R _{0JA} | Free Air Operation | | - | - | 30 | °C/W |

Source to Drain Diode Specifications

| PARAMETER | SYMBOL | TEST CONDI | ITIONS | MIN | ТҮР | MAX | UNITS |
|--|-----------------|--|--------|-----|------|-----|-------|
| Continuous Source to Drain Current | I _{SD} | Modified MOSFET Symbol | | - | - | 14 | A |
| Pulse Source to Drain Current (Note 3) | ISDM | Showing the Integral Reverse P-N Junction Rectifier | Go U S | - | - | 56 | A |
| Source to Drain Diode Voltage (Note 2) | V _{SD} | $T_J = 25^{\circ}C$, $I_{SD} = 14A$, $V_{GS} = 0V$ (Figure 13) | | - | - | 1.4 | V |
| Reverse Recovery Time | t _{rr} | $T_{J} = 150^{o}C$, $I_{SD} = 13A$, $dI_{SD}/dt = 100A/\mu s$ | | - | 1300 | - | ns |
| Reverse Recovery Charge | Q _{RR} | $T_J = 150^{o}C$, $I_{SD} = 13A$, $dI_{SD}/dt = 100A/\mu s$ | | - | 7.4 | - | μC |

NOTES:

2. Pulse test: pulse width \leq 300 μ s, duty cycle \leq 2%.

- 3. Repetitive rating: pulse width limited by Max junction temperature. See Transient Thermal Impedance curve (Figure 3).
- 4. V_{DD} = 50V, starting T_J = 25^oC, L = 7.9mH, R_G = 25 Ω , peak I_{AS} = 14A.



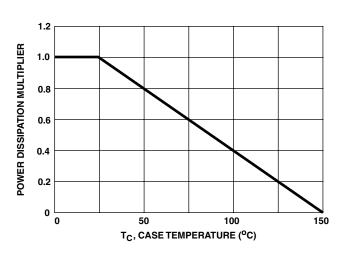


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

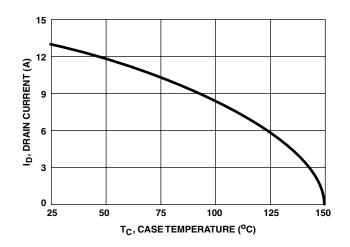
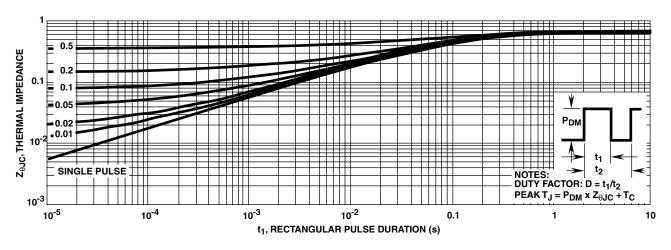


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE





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Typical Performance Curves Unless Otherwise Specified (Continued)

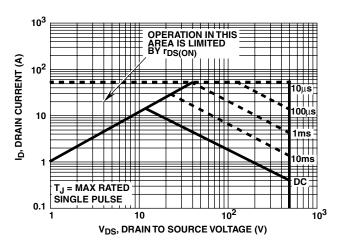


FIGURE 4. FORWARD BIAS SAFE OPERATING AREA

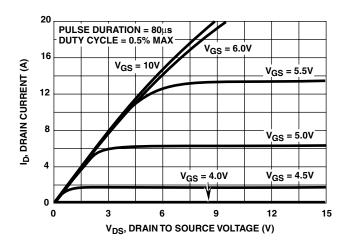
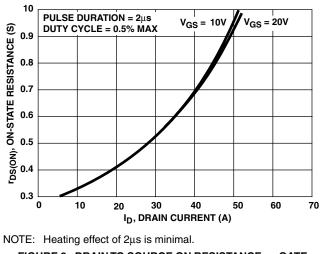
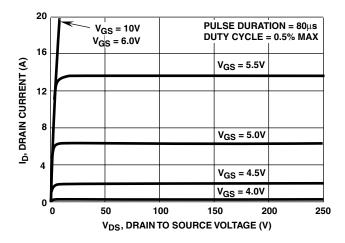


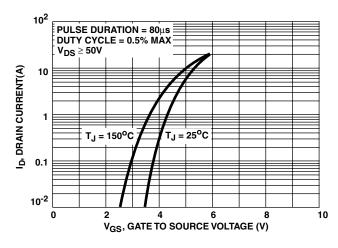
FIGURE 6. SATURATION CHARACTERISTICS













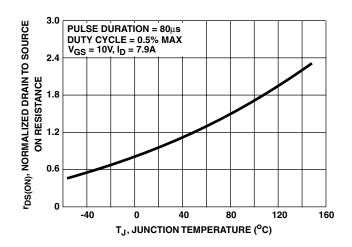
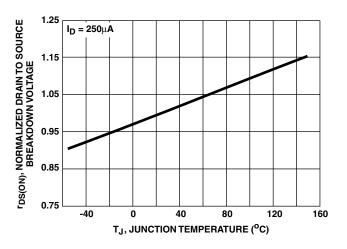


FIGURE 9. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

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Typical Performance Curves Unless Otherwise Specified (Continued)





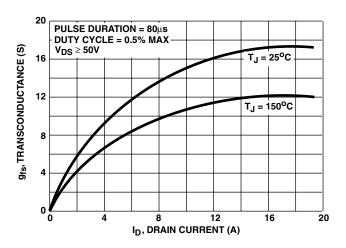


FIGURE 12. TRANSCONDUCTANCE vs DRAIN CURRENT

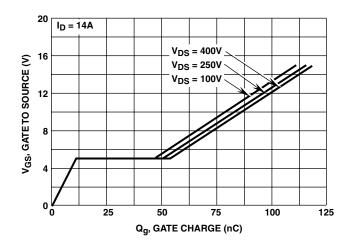


FIGURE 14. GATE TO SOURCE VOLTAGE vs GATE CHARGE

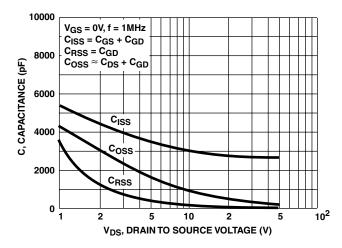


FIGURE 11. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

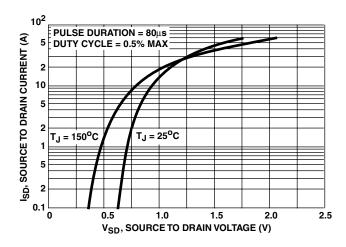


FIGURE 13. SOURCE TO DRAIN DIODE VOLTAGE

Test Circuits and Waveforms

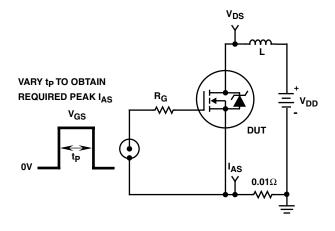


FIGURE 15. UNCLAMPED ENERGY TEST CIRCUIT

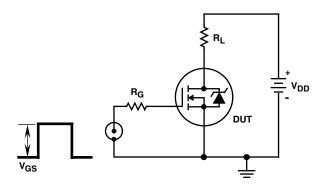


FIGURE 17. SWITCHING TIME TEST CIRCUIT

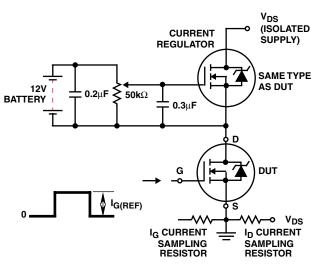


FIGURE 19. GATE CHARGE TEST CIRCUIT



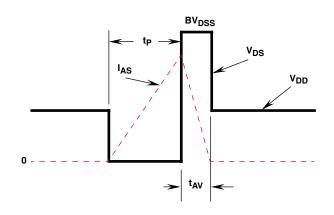


FIGURE 16. UNCLAMPED ENERGY WAVEFORMS

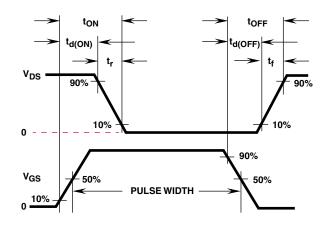


FIGURE 18. RESISTIVE SWITCHING WAVEFORMS

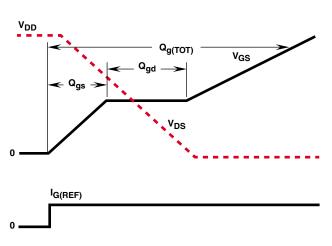


FIGURE 20. GATE CHARGE WAVEFORMS

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